Se	arch	h Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/696,118	LEACH ET AL.	
Examiner	Art Unit	
James Mackey	1722	

	SEAR	CHED	
Class	Subclass	Date	Examiner
425	190,193, 194, 195, 470, 471	12/11/2005	JPM

INT	ERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
<u> </u>			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Conducted INVENTOR name search in IFW	12/11/2005	JPM	
Reviewed related applications S.N. 09/576,831; 10/724,649	12/12/2005	JPM	
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